

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims

1. (Canceled)
2. (Previously presented) The probe module of claim 7, wherein each of the plurality of probe pins further comprises a probe pin head extending from the probe pin body and a generally tapered probe pin tip provided on the probe pin head.
3. (Previously presented) The probe module of claim 7, wherein the circuit interconnect device comprises a plurality of conductive probe circuits provided on the probe base in electrical contact with the plurality of probe pins, respectively, and a flexible circuit board provided in electrical contact with the plurality of conductive probe circuits.
4. (Canceled)
5. (Previously presented) The probe module of claim 7, wherein each of the plurality of probe pins further comprises a probe pin head extending from the probe pin body and a generally semi-spherical probe pin tip provided on the probe pin head.
6. (Canceled)
7. (Currently amended) A probe module for testing an LCD panel having a plurality of test points comprising:

a probe base having a plurality of conductive metal traces;

a plurality of completely exposed probe pins attached to the probe base, each of the probe pins comprising an elongate body, wherein at least part of the elongated body is bonded to at least one of the plurality of conductive metal traces of the probe base;

a flexible circuit interconnect device for connecting the plurality of probe bins to an inspection apparatus;

a flexible compression arm attached to a probe base and configured to engage the plurality of probe pins; and

at least one adjustment element provided on the probe base ~~that adjusts~~ configured to adjust a pressure of the flexible compression arm against the plurality of probe pins during testing of the LCD panel so as to adjust a contact angle of the probe pins with respect to the test points.

8-12. (Canceled)

13. (Previously presented) The probe module of claim 7 wherein the plurality of probe pins have a generally tetrahedral probe pin tip.

14-21. (Canceled)

22. (Previously presented) The probe module of claim 7, wherein the flexible circuit interconnect device couples the probe pins to a testing unit via the conductive metal traces.

23. (Canceled)

24. (Previously presented) The probe module of claim 7, wherein the probe pins include a probe head having at least one of a tapered, semi-spherical, inverted-pyramid or a tetrahedral shape.

25. (Previously presented) The probe module of claim 7, wherein the probe pins include an elongated arm body such that at least a part of the elongated arm body is attached with the probe base.

26-33. (Canceled)

34. (Previously presented) The probe module of claim 7, wherein the adjustment element is a screw.
35. (Previously presented) The probe module of claim 7, wherein the flexible compression arm comprises plastic.
36. (Previously presented) The probe module of claim 7, wherein the flexible compression arm comprises metal.
37. (Previously presented) The probe module of claim 7, wherein a pitch between adjacent ones of the plurality of probe pins is about 30 μm .
38. (New) The probe module of claim 7, wherein the adjustment element is a micro-adjustable adjustment screw.
- 39 (New) A probe module for testing an LCD panel having a plurality of test points comprising:
- a probe base having a plurality of conductive metal traces;
 - a plurality of completely exposed probe pins attached to the probe base, each of the probe pins comprising an elongate body, wherein at least part of the elongated body is bonded to at least one of the plurality of conductive metal traces of the probe base;
 - a flexible circuit interconnect device for connecting the plurality of probe pins to an inspection apparatus;
 - a flexible compression arm attached to a probe base and configured to engage the plurality of probe pins; and
 - at least one adjustment element provided on the probe base for adjustably increasing and decreasing a pressure of the flexible compression arm on the plurality of probe pins

during testing of the LCD panel so as to adjust a pressure of the probe pins on the test points.